

16-Channel and Dual 8-Channel Latchable Multiplexers

FEATURES

- TTL Compatible
- 44 V Power Supply Rating
- On-board Address Latches
- $r_{DS(ON)} < 400 \Omega$
- Break-Before-Make

BENEFITS

- Easily Interfaced
- Increased Analog Signal Range
- Microprocessor Bus Compatible
- Improved System Accuracy
- Reduced Crosstalk

APPLICATIONS

- Data Acquisition Systems
- Automatic Test Equipment
- Avionics And Military Systems
- Communication Systems
- Microprocessor Controlled Systems
- Audio Signal Multiplexing

DESCRIPTION

DG526 and DG527 are 16 and 8-channel analog multiplexers, respectively, with on-chip address and control latches to simplify design in microprocessor based applications. Break-Before-Make switching action protects against momentary shorting of the input signals. Designed on the Siliconix PLUS-40 CMOS process, each bidirectional switch features low 400 Ω ON resistance over the full analog range, and will block signals to 30 V peak-to-peak in the unselected channels. All logic levels are TTL-compatible. An epitaxial layer prevents latch up.

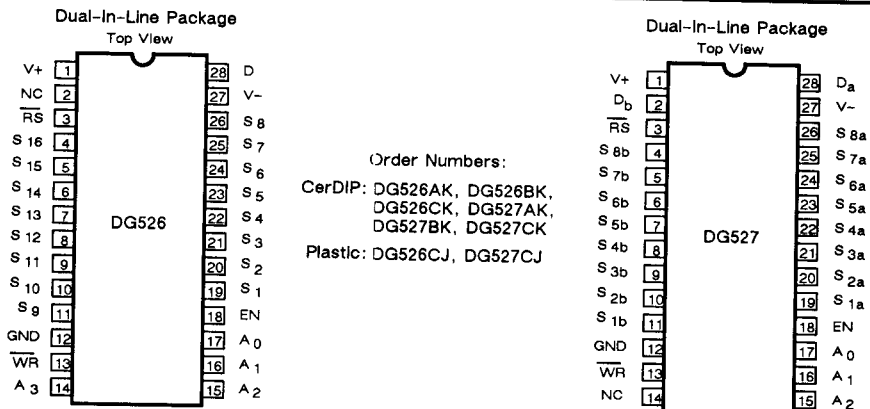
DG526 is a 16-channel single-ended analog multiplexer designed to connect 1 of 16 inputs to a common output as determined by a 4-bit binary address (A_0, A_1, A_2, A_3). DG527, an 8-channel

dual analog multiplexer, is designed to connect 1 of 8 differential inputs to a common differential output as determined by its 3-bit binary address (A_0, A_1, A_2) logic.

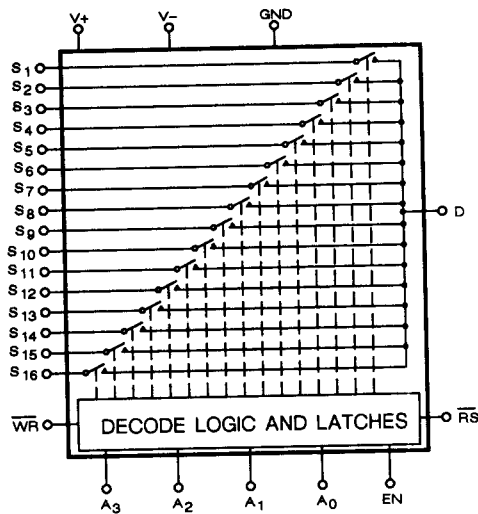
The on-board TTL-compatible address latches simplify the digital interface design and reduce board space in bus-controlled systems such as data acquisition systems, process controls, avionics, and ATE. The DG526 is available in 28-pin CerDIP in the military, A suffix (-55 to 125°C), industrial, B suffix (-25 to 85°C) temperature ranges, and in the plastic DIP for commercial, C suffix (0 to 70°C) temperature operation.

For more information on the DG526 and DG527, please refer to Siliconix Application Note AN83-4.

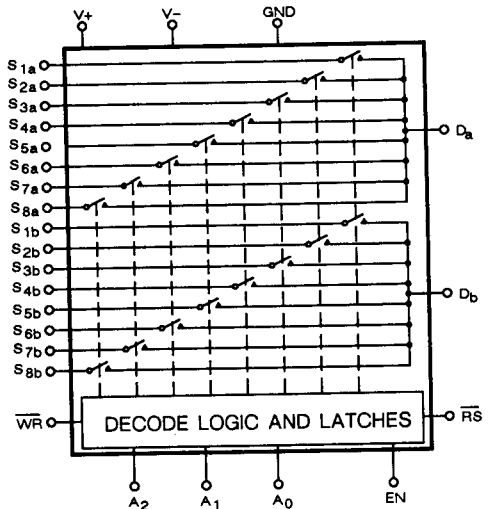
PIN CONFIGURATION



FUNCTIONAL BLOCK DIAGRAM



DG526
16 Channel Single Ended Multiplexer



DG527
Differential 8 Channel Multiplexer

ABSOLUTE MAXIMUM RATINGS

Voltage Referenced to V-

V+	44 V
GND	25 V
Digital inputs, V_S , V_D^h	(V-) -2 V to (V+) +2 V or 20 mA, whichever occurs first.
Current (Any Terminal Except S or D)	30 mA
Continuous Current, S or D	20 mA
Peak Current, S or D (Pulsed at 1 ms, 10% Duty Cycle Max)	40 mA

Operating Temperature (A Suffix)	-55 to 125°C
(B Suffix)	-25 to 85°C
(C Suffix)	0 to 70°C
Storage Temperature (A & B Suffix)	-65 to 150°C
(C Suffix)	-65 to 125°C

Power dissipation (Package) *

28-Pin CerDIP DIP**	1046 mW
28-Pin Plastic DIP**	1046 mW

* All leads soldered or welded to PC board.

** Derate 6.5 mW/°C above 25°C.

ELECTRICAL CHARACTERISTICS ^a							
PARAMETER	SYMBOL	Test Conditions Unless Otherwise Specified: V _D = 15 V, V ₋ = -15 V GND = 0, \overline{WR} = 0 RS = 2.4 V	LIMITS				UNIT
			1=25 °C 2=125,70,85 °C 3=-55,-25,0 °C		ALL SUFFIXES		
			TEMP	TYP ^d	MIN ^b	MAX ^b	
SWITCH							
Analog Signal Range ^c	V _{ANALOG}		1,2,3		-15	15	V
Drain-Source ^e ON Resistance	r _{DS(ON)}	V _D = ±10 V, V _{AL} = 0.8 V I _S = -200 μA, V _{AH} = 2.4 V	1, 3 2	250		400 500	Ω
Greatest Change In r _{DS(ON)} Between Channels ^f	r _{DS(ON)} Δ	-10 V < V _S < 10 V	1	6			%
Source OFF Leakage Current	I _{S(OFF)}	V _{EN} = 0 V	V _S = ±10 V V _D = ∓10 V	1 2	0.02	-1 -50	1 50
Drain OFF Leakage Current	I _{D(OFF)}		V _D = ±10 V V _S = ∓10 V	1 2	0.2	-10 -300	10 300
			V _D = ±10 V V _S = ∓10 V	1 2	0.2	-10 -200	10 200
Drain ON Leakage Current ^{e,g}	I _{D(ON)}		V _S = V _D = ±10 V V _{EN} = 2.4 V	1 2	0.2	-10 -300	10 300
		V _{AL} = 0.8 V V _{AH} = 2.4 V	1 2	0.2	-10 -200	10 200	
INPUT							
Logic Input Current Input Voltage High	I _{AH}	V _A = 2.4 V	1 2	0.02	-10 -30	20 30	μA
		V _A = 15 V	1 2	0.02	-10 -30	10 30	
Logic Input Current Input Voltage Low	I _{AL}	V _{EN} = 0 or 2.4 V, V _A = 0 V RS = 0 V, WR = 0 V	1 2	0.01	-10 -30	10 30	
DYNAMIC							
Switching Time of Multiplexer	t _{TRANS}	See Figure 3	1	0.65		1	μs
Break-Before-Make Interval	t _{OPEN}	See Figure 5	1	0.2			
Enable and Write Turn ON Time	t _{ON(EN,WR)}	See Figure 4 and 6	1	0.7		1.5	
Enable and Reset Turn OFF Time	t _{OFF(EN,RS)}	See Figure 4 and 7	1	0.4		1	
Charge Injection	Q	See Figure 8	1	10			pC
OFF Isolation		V _{EN} = 0, R _L = 1 kΩ C _L = 15 pF, V _S = 7 V _{RMS} f = 500 kHz	1	55			dB
Logic Input Capacitance	C _{in}	f = 1 MHz	1	6			pF

ELECTRICAL CHARACTERISTICS ^a									
PARAMETER	SYMBOL	Test Conditions Unless Otherwise Specified: V ₊ = 15 V, V ₋ = -15 V GND = 0, WR = 0 RS = 2.4 V	LIMITS				UNIT		
			1=25 °C		2=125,70,85 °C				
			3=-55,-25,0 °C		ALL SUFFIXES				
			TEMP	TYP ^d	MIN ^b	MAX ^b			
DYNAMIC (Cont'd)									
Source OFF Capacitance	C _{S(OFF)}	V _{EN} = 0 f = 140 kHz	V _S = 0	1	10			PF	
Drain OFF Capacitance	DG526		C _{D(OFF)}	V _D = 0	1	65			
	DG527				1	35			
MINIMUM INPUT TIMING REQUIREMENTS									
WR Pulse Width	t _{WW}	See Figure 1	1,2,3	260	300			ns	
A _X , EN Data Valid to WR	t _{DW}	(Stabilization Time) See Figure 1	1,2,3	150	180				
A _X , EN Data Valid after WR	t _{WD}	(Hold Time) See Figure 1	1,2,3	20	30				
RS Pulse Width ⁱ	t _{RS}	See Figure 2 V _S = 5 V	1,2,3	350	500				
SUPPLY									
Positive Supply Current	I ₊	V _{EN} = 0, V _A = 0	1,2,3	2.0		3.0 4.5	mA		
Negative Supply Current	I ₋		1,2,3	-1.2	-2.0 -3.2				

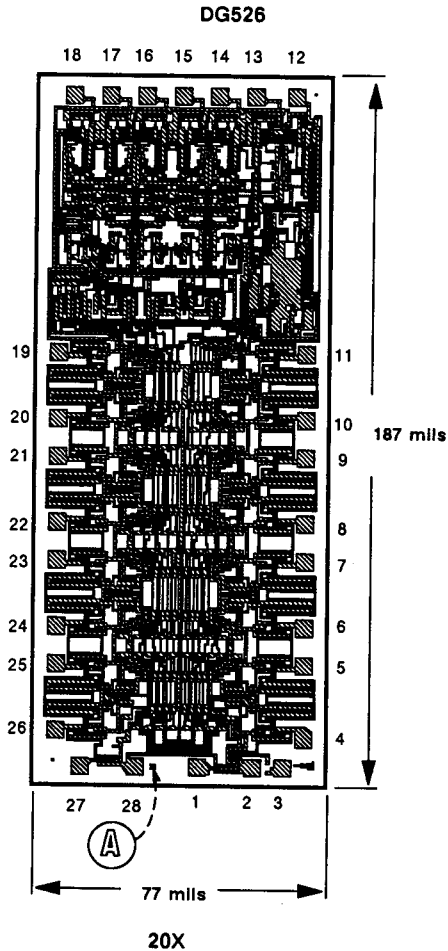
NOTES:

- a. Refer to PROCESS OPTION FLOWCHART for additional information.
- b. The algebraic convention whereby the most negative value is a minimum and the most positive a maximum, is used in this data sheet.
- c. Guaranteed by design, not subject to production test.
- d. Typical values are for DESIGN AID ONLY, not guaranteed nor subject to production testing.
- e. Sequence each switch ON.

$$f. \Delta r_{DS(ON)} = \left(\frac{r_{DS(ON) MAX} - r_{DS(ON) MIN}}{r_{DS(ON) AVE}} \right)$$

- g. I_{D(ON)} is leakage from driver into "ON" switch.
- h. Signals on S_X, D_X, IN_X exceeding V₊ or V₋ will be clamped by internal diodes. Limit forward diode current to maximum current ratings.
- i. Period of Reset (RS) pulse must be at least 50 μs during or after power ON.

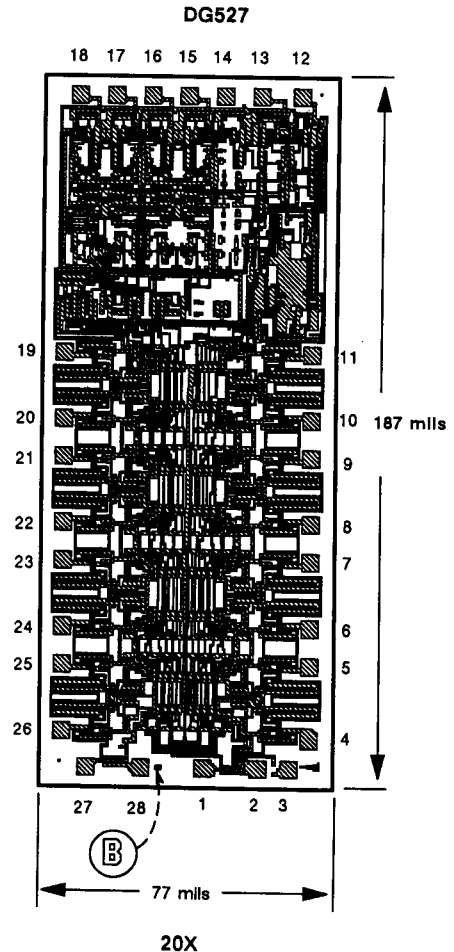
DIE TOPOGRAPHIES



Pad No.	Function	Pad No.	Function
1	V+ (substrate)	15	A ₂
2	No connection	16	A ₁
3	RS	17	A ₀
4	S ₁₆	18	EN
5	S ₁₅	19	S ₁
6	S ₁₃	20	S ₂
7	S ₁₄	21	S ₃
8	S ₁₂	22	S ₄
9	S ₁₁	23	S ₅
10	S ₁₀	24	S ₆
11	S ₉	25	S ₇
12	GND	26	S ₈
13	WR	27	V-
14	A ₃	28	D

ICMNA

- | | |
|----------------|----------------------------------|
| 10 Resistors | 177 P-channel enhancement MOSFET |
| 14 Diodes | 201 N-channel enhancement MOSFET |
| 2 Zener Diodes | 2 PNP Bipolar Transistors |

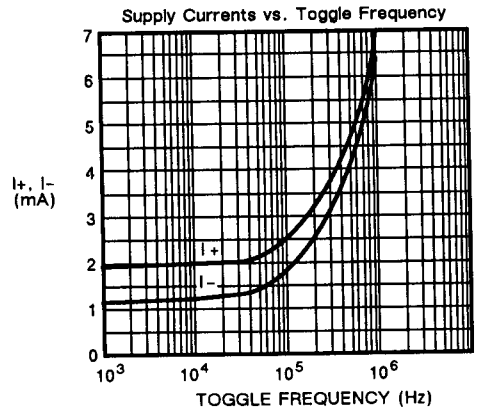
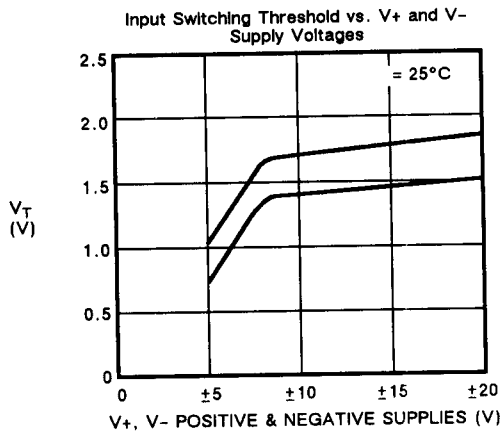
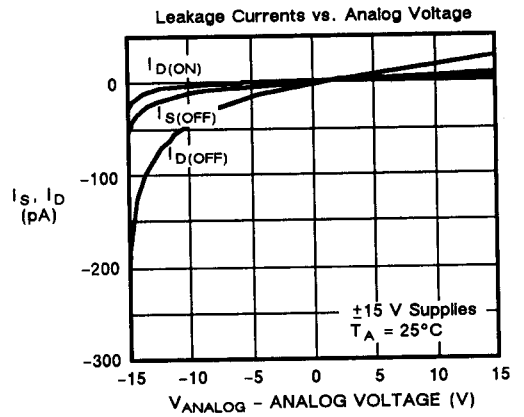
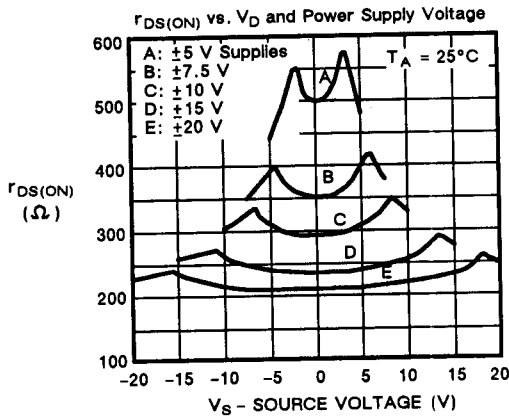


Pad No.	Function	Pad No.	Function
1	V+ (substrate)	15	A ₂
2	D	16	A ₁
3	RS	17	A ₀
4	S _{8b}	18	EN
5	S _{7b}	19	S _{1a}
6	S _{6b}	20	S _{2a}
7	S _{5b}	21	S _{3a}
8	S _{4b}	22	S _{4a}
9	S _{3b}	23	S _{5a}
10	S _{2b}	24	S _{6a}
11	S ₉	25	S _{7a}
12	GND	26	S _{8a}
13	WR	27	V-
14	No Connection	28	D _a

ICMNB

- | | |
|----------------|----------------------------------|
| 9 Resistors | 164 P-channel enhancement MOSFET |
| 16 Diodes | 189 N-channel enhancement MOSFET |
| 2 Zener Diodes | 2 PNP Bipolar Transistors |

TYPICAL CHARACTERISTICS



TRUTH TABLES

DG526

A ₃	A ₂	A ₁	A ₀	EN	\overline{WR}	\overline{RS}	On Switch
Latching							
X	X	X	X	X		1	Maintains previous switch condition
Reset							
X	X	X	X	X	X	0	NONE (latches cleared)
Transparent Operation							
X	X	X	X	0	0	1	NONE
0	0	0	0	1	0	1	1
0	0	0	1	1	0	1	2
0	0	1	0	1	0	1	3
0	0	1	1	1	0	1	4
0	1	0	0	1	0	1	5
0	1	0	1	1	0	1	6
0	1	1	0	1	0	1	7
0	1	1	1	1	0	1	8
1	0	0	0	1	0	1	9
1	0	0	1	1	0	1	10
1	0	1	0	1	0	1	11
1	0	1	1	1	0	1	12
1	1	0	0	1	0	1	13
1	1	0	1	1	0	1	14
1	1	1	0	1	0	1	15
1	1	1	1	1	0	1	16

DG527

A ₂	A ₁	A ₀	EN	\overline{WR}	\overline{RS}	On Switch
Latching						
X	X	X	X		1	Maintains previous switch condition
Reset						
X	X	X	X	X	0	NONE (latches cleared)
Transparent Operation						
X	X	X	0	0	1	NONE
0	0	0	1	0	1	1
0	0	1	1	0	1	2
0	1	0	1	0	1	3
0	1	1	1	0	1	4
1	0	0	1	0	1	5
1	0	1	1	0	1	6
1	1	0	1	0	1	7
1	1	1	1	0	1	8

Logic "1": $V_{AH} > 2.4 V$

Logic "0": $V_{AL} < 0.8 V$

TIMING DIAGRAMS

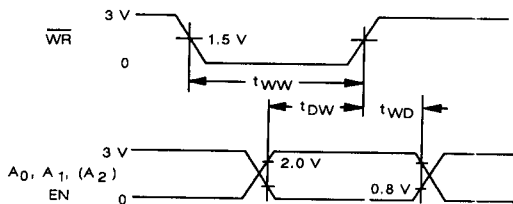


Figure 1

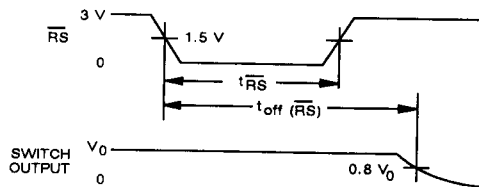


Figure 2

TRANSITION TIME TEST CIRCUIT

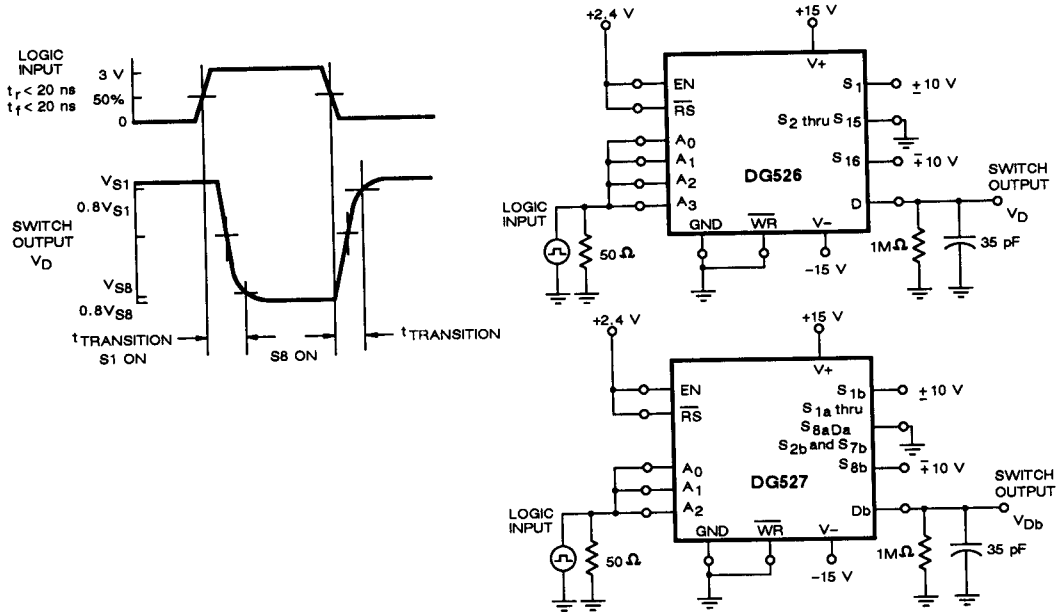


Figure 3

ENABLE t_{ON}/t_{OFF} TIME TEST CIRCUIT

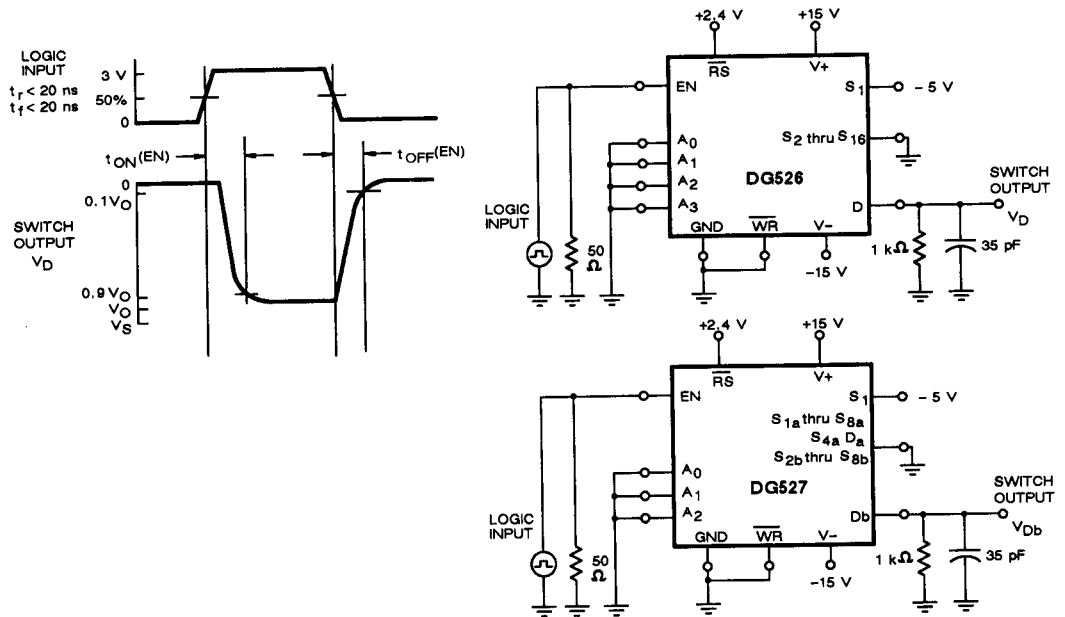


Figure 4

OPEN TIME (B.B.M.) INTERVAL TEST CIRCUIT

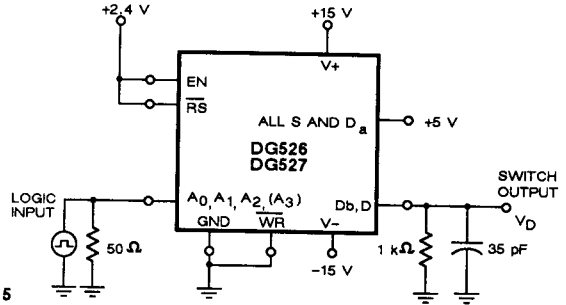
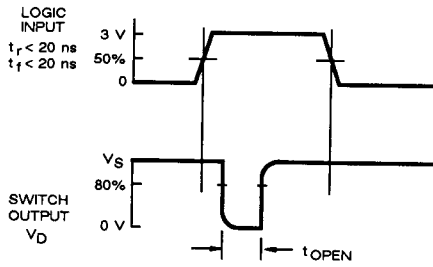


Figure 5

WRITE TURN-ON TIME $t_{ON}(\overline{WR})$ TEST CIRCUIT

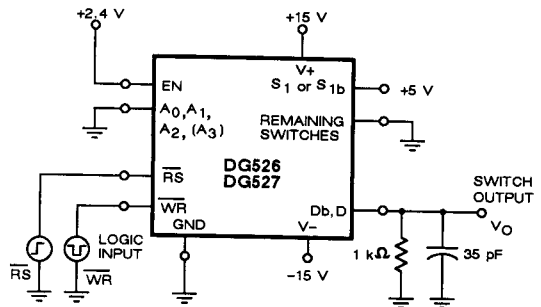
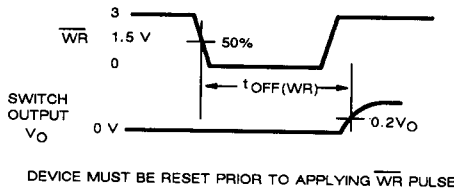


Figure 6

RESET TURN-OFF TIME $t_{OFF}(\overline{RS})$ TEST CIRCUIT

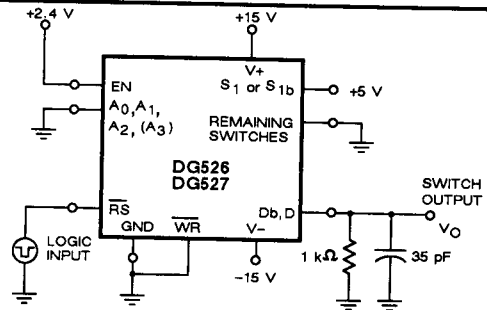
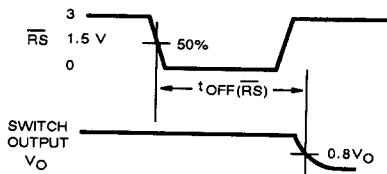
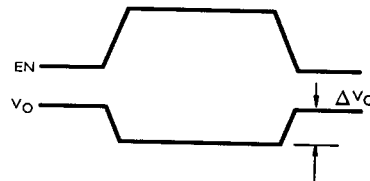
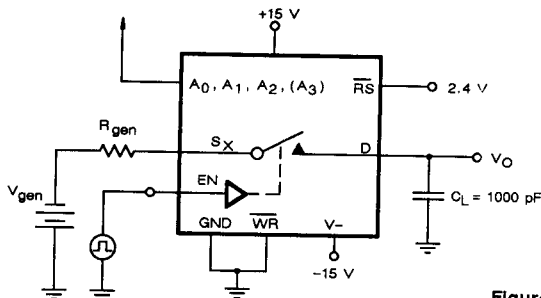


Figure 7

CHARGE INJECTION TEST CIRCUIT



ΔV_0 IS THE MEASURED VOLTAGE ERROR DUE TO CHARGE INJECTION. THE CHARGE IN COULOMBS IS $Q = C_L \times \Delta V_0$

Figure 8

DETAILED DESCRIPTION

The internal structure of the DG526 and DG527 includes a 5 V logic interface with input protection circuitry followed by a latch, level shifter, decoder and finally the switch constructed with parallel N and P-channel MOSFETs (see figure 9).

The input protection on the logic lines A_0 , A_1 , A_2 , A_3 , EN and control lines \overline{WR} , \overline{RS} shown in figure 9 minimize susceptibility to static encountered during handling and operational transients.

The logic interface circuit compares the TTL input signal against a TTL threshold reference voltage. The output of the comparator feeds the data input of a D type latch. The level sensitive D latch continuously places the D_x input signal on the Q_x output when the CLK (\overline{WR}) input is low, resulting in transparent operation. As soon as CLK (\overline{WR}) returns high the latch holds the data last present on

the D_x input at the Q_x output, subject to the "Minimum Input Timing Requirements" table.

Following the latches the Q_x signals are level shifted and decoded to provide proper drive levels for the CMOS switches. This level shifting insures full ON/OFF switch operation for any analog signal present between the V_+ and V_- supply pins.

The enable (EN) pin is used to enable the address latches during the \overline{WR} pulse. It can be hard wired to the logic supply if one of the channels will always be used (except during a reset) or it can be tied to address decoding circuitry for memory mapped operation. The \overline{RS} pin is used as a master reset. All latches are cleared regardless of the state of any other latch or control line. The \overline{WR} pin is used to transfer the state of the address control lines to their latches, except during a reset or when EN is low (see Truth Tables).

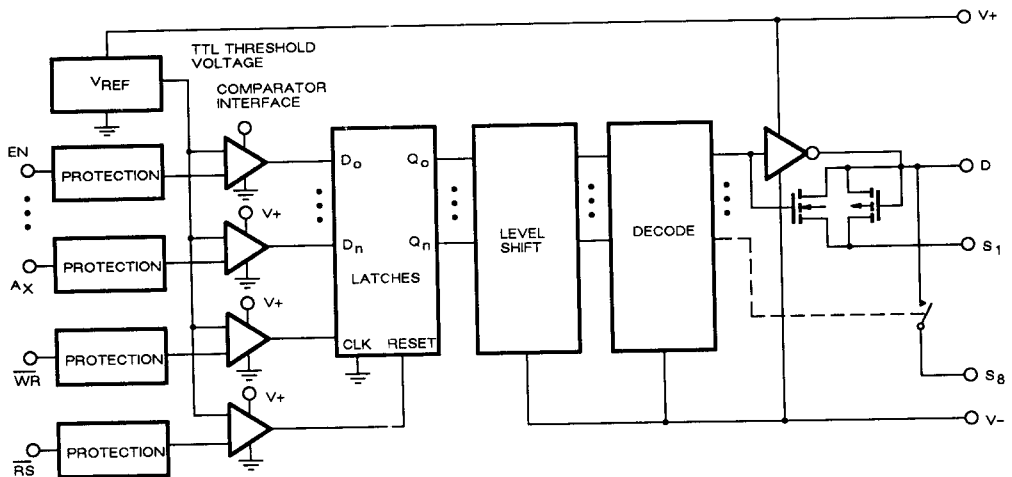


Figure 9. DG526/527 Simplified Internal Structure

APPLICATIONS

INTRODUCTION

The DG526 and DG527 minimize the amount of interface hardware between a microprocessor system bus and the analog system being controlled or measured. The internal TTL compatible latches give these multiplexers write-only memory, that is, they can be programmed to stay in a particular

switch state (e.g., switch 1 ON) until the microprocessor determines it is necessary to turn different switches ON or turn all switches OFF.

The input latches become transparent when \overline{WR} is held low; therefore, these multiplexers operate by direct command of the coded switch state on the address inputs. In this mode the DG526 is identical

APPLICATIONS (Cont'd)

to the very popular DG506 even sharing the same pin locations. The same is true of the DG527 versus the popular DG507.

CIRCUIT OPERATION (See Figure 10)

Initially during system power-up \overline{RS} would be active LOW maintaining all 16 switches in the OFF state. After \overline{RS} returned HIGH the DG526 maintains all switches in the OFF state. As soon as the system program was ready to perform a write operation to the address assigned to the DG526, the address decoder would provide a \overline{CS} active LOW signal which is gated with the WRITE (\overline{WR}) control signal. At this time the data on the DATA BUS (that will determine which switch to close) is stabilizing. When the \overline{WR} signal returns to the HIGH state, (positive edge) the input latches of the DG526 save the data from the DATA BUS. The coded

information in the $A_0, A_1, A_2, A_3,$ and EN latches is decoded and the appropriate switch is turned ON.

The EN latch allows all switches to be turned OFF under program control. This becomes useful when two or more DG526s are cascaded to build 32-line and larger analog signal input multiplexers.

Figure 11 illustrates one use of the DG527. Dual multiplexers are generally used with differential or instrumentation amplifiers in process control applications to eliminate errors due to common mode signals. In this circuit however, advantage is taken of the dual multiplexing capability of the switch. This is achieved by using the multiplexer to select pairs of R.C. networks to control the pulse width of the multivibrator. This can be a particularly useful feature in process control applications where there is a requirement for a variable width sample "window" for different control signals.

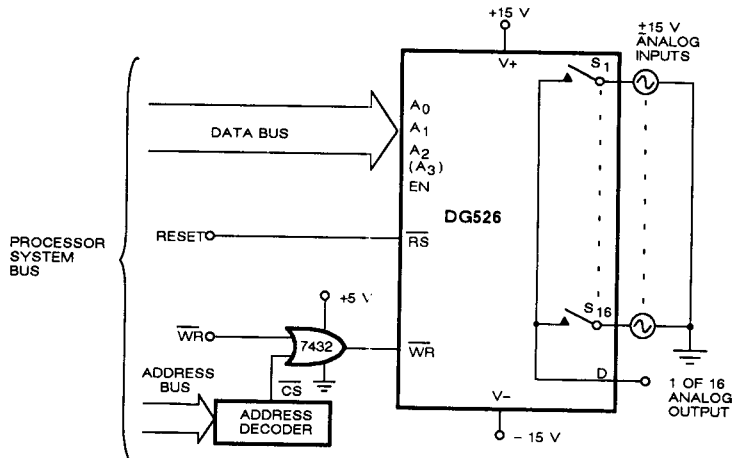


Figure 10

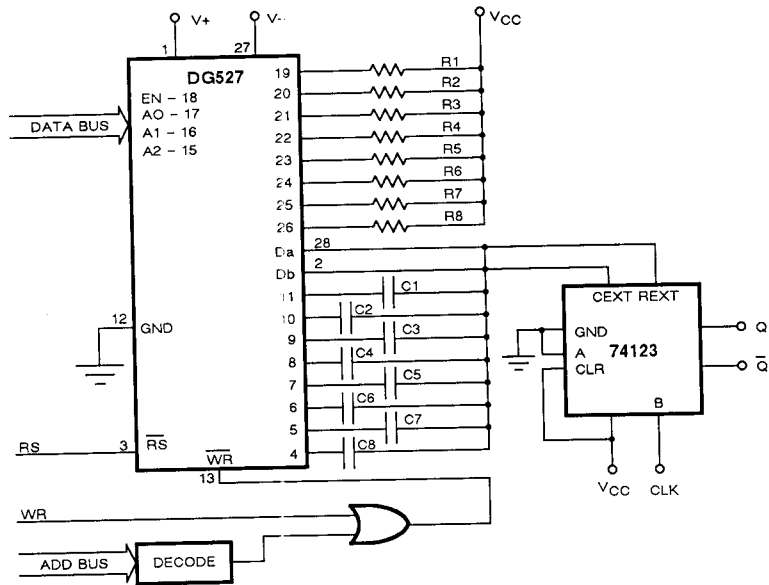


Figure 11. μ P-selected Pulse-Width Control

APPLICATIONS HINTS

V+ Positive Supply Voltage (V)	V- Negative Supply Voltage (V)	GND Analog & Power Supply GND (V)	V _{IN} Logic Input Voltage V _{INH} Min/ V _{INL} Max (V)	V _S or V _D Analog Voltage Range (V)
20	-20	GND	2.4/0.8	± 20
15	-15	GND	2.4/0.8	± 15
8	-8	GND	2.4/0.8	± 8